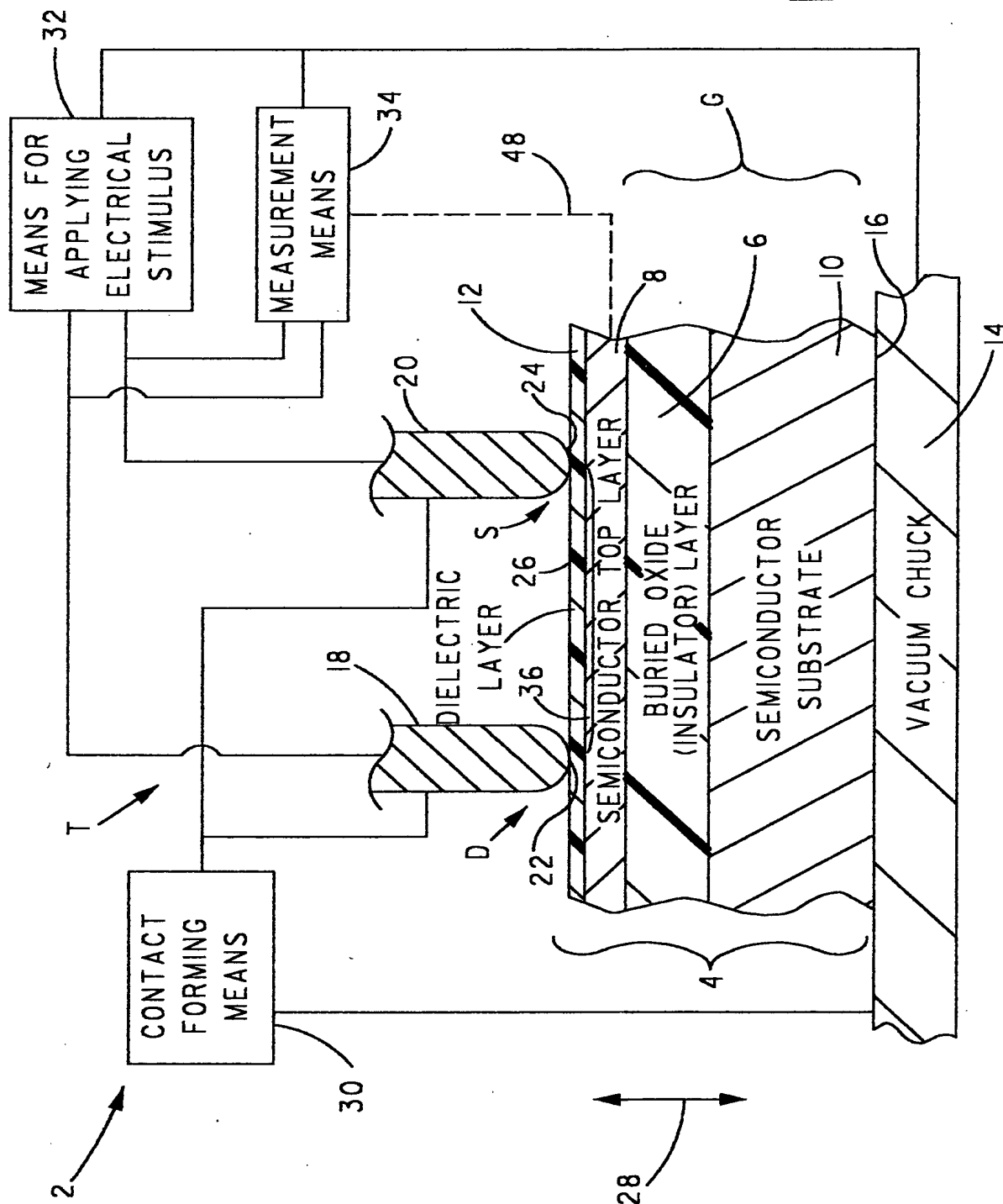




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FILE



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WAFER"

Attorney Docket No.: 1880-031249 Application No.: 10/701,841



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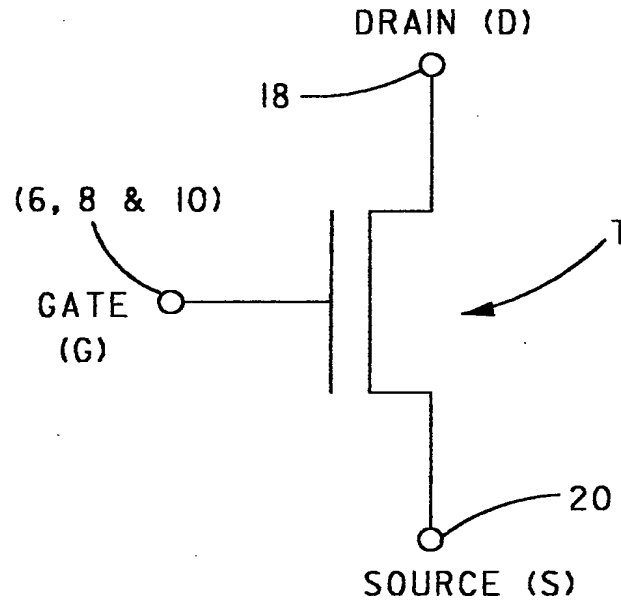


FIG. 2

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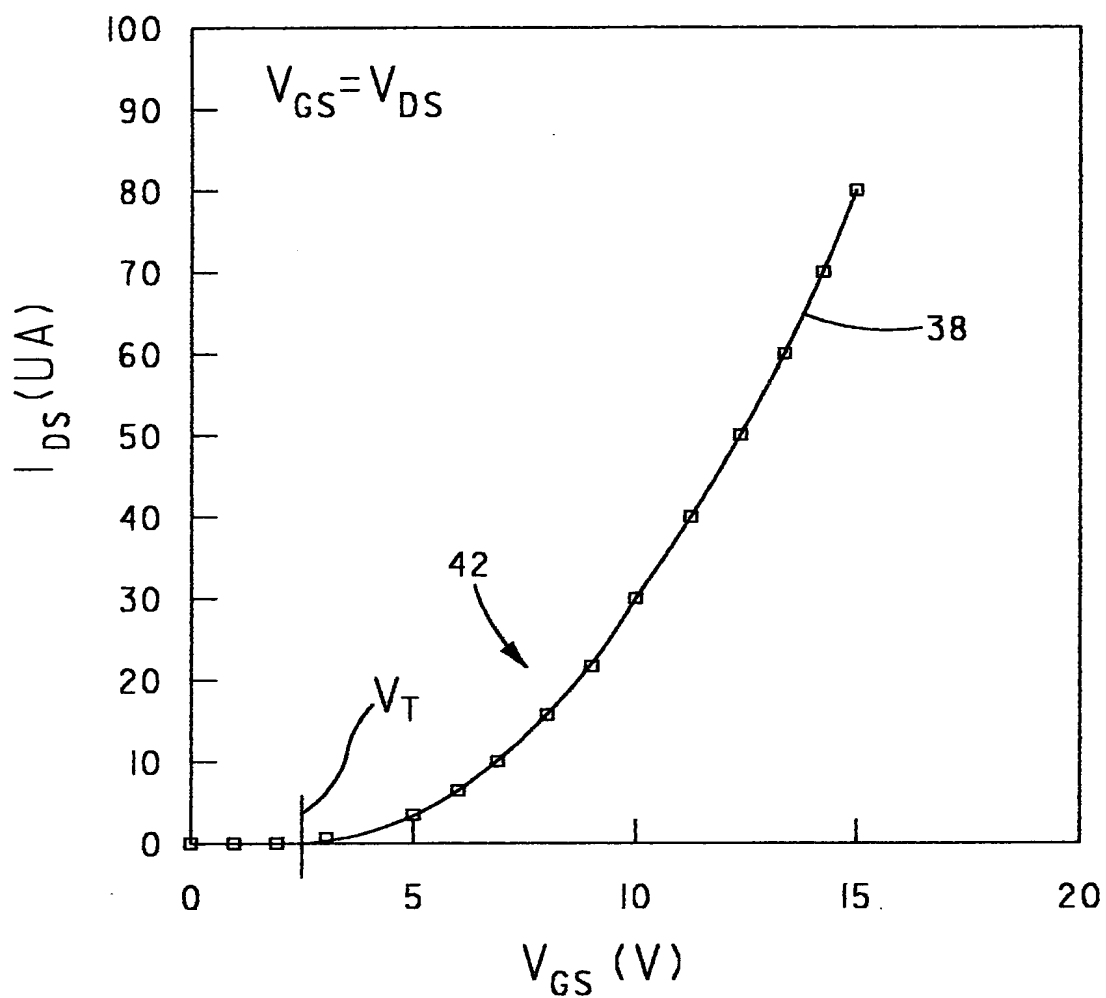


FIG. 3

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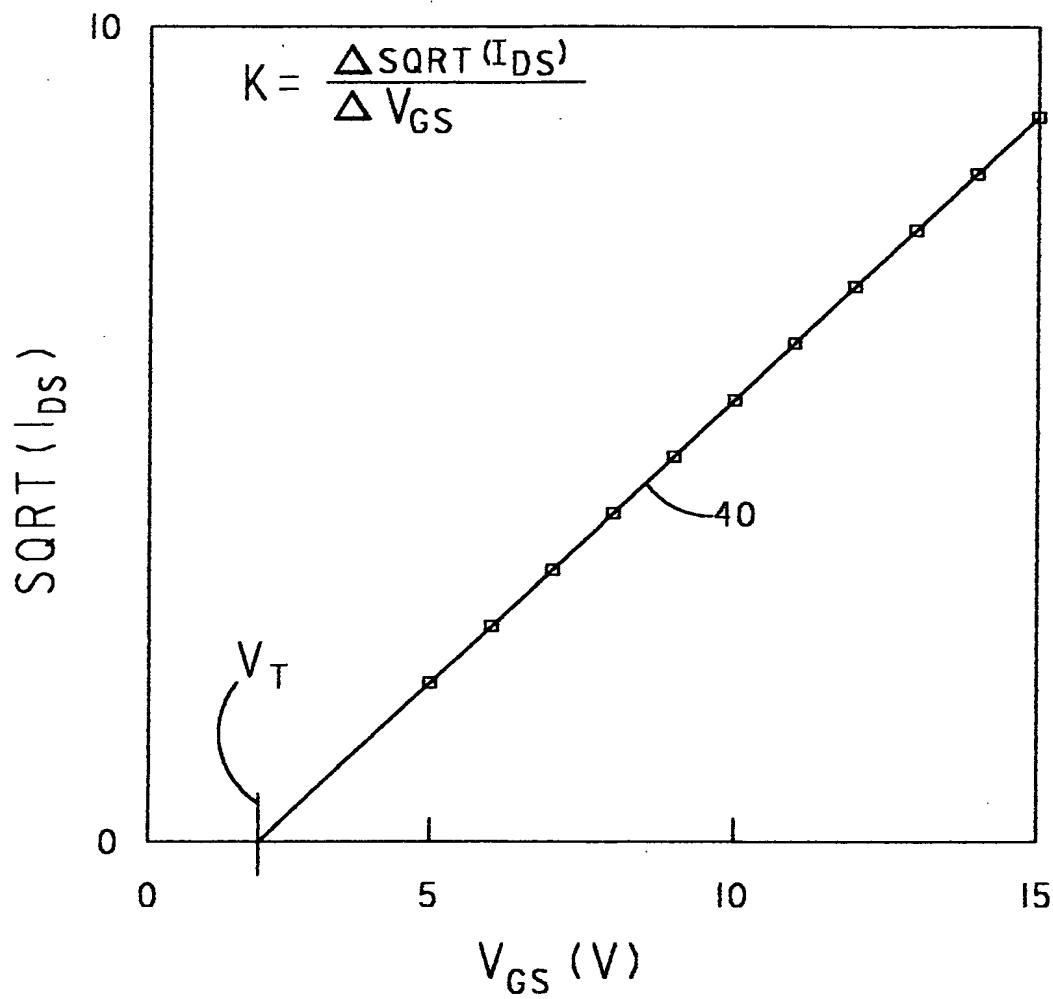


FIG. 4

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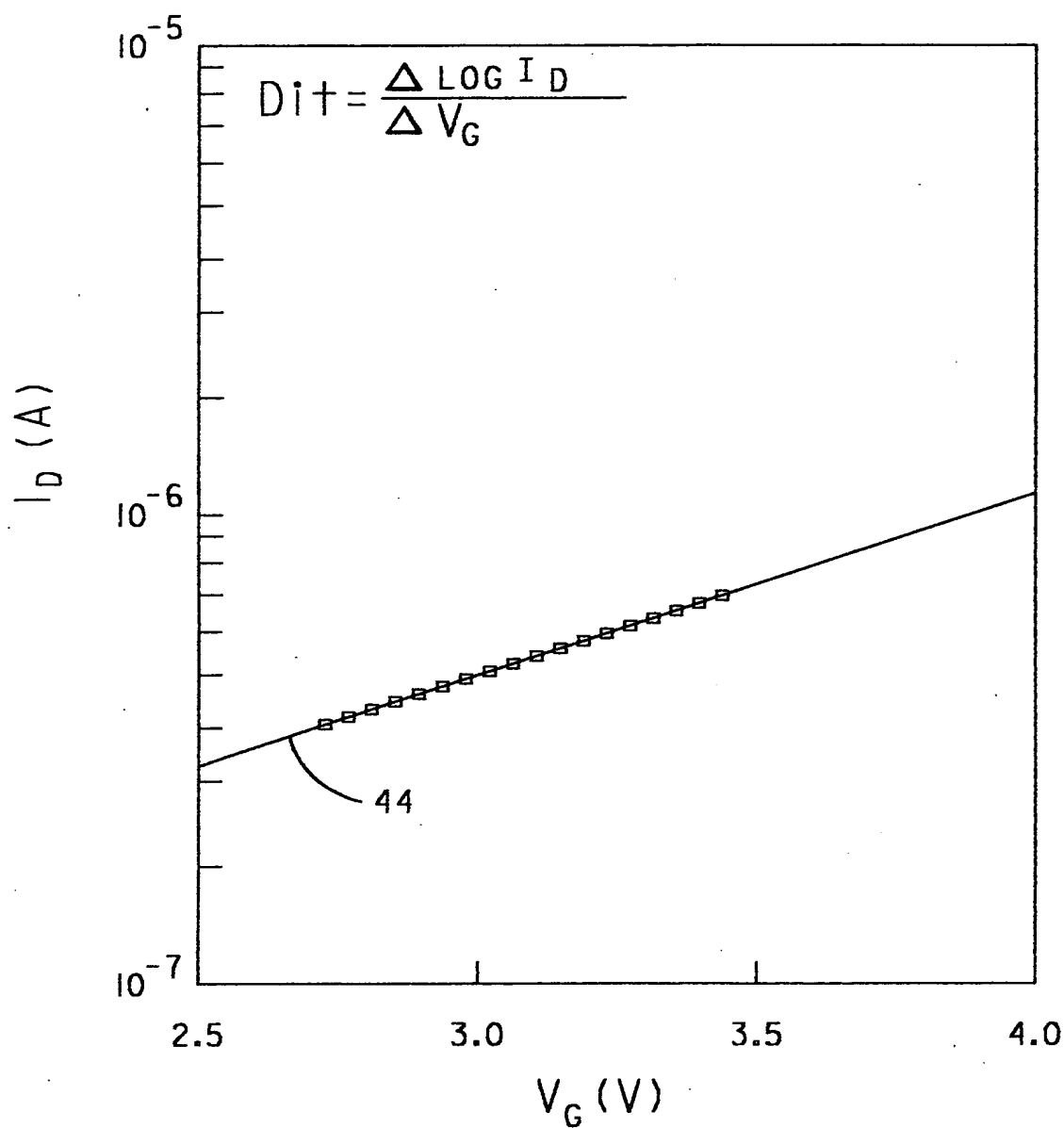


FIG. 5

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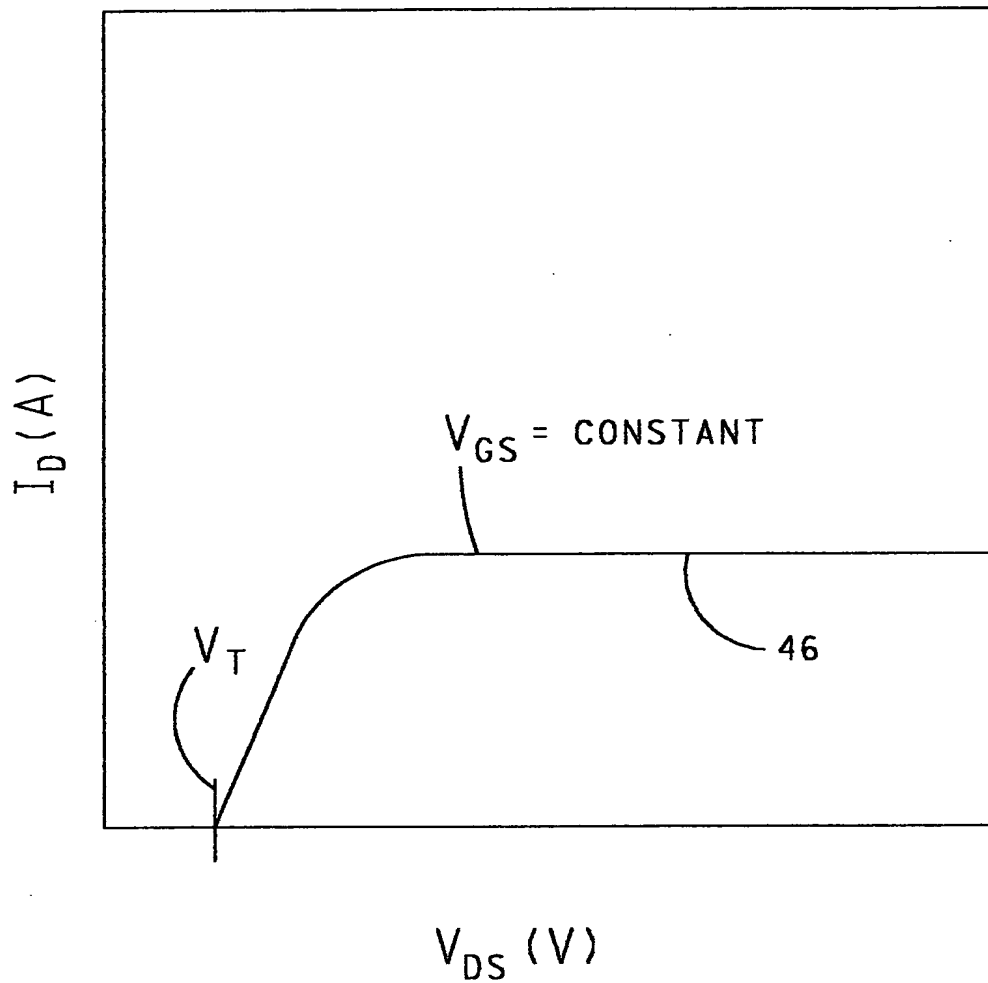


FIG. 6